Notice of References Cited Application/Control No. 10/765,936 Examiner Chuck Huynh Applicant(s)/Patent Under Reexamination BARKAN, YUVAL Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0009774	01-2004	Kotzin et al.	455/450
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